X-ray tomography on CICC conductors and joints

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TS 2019

Deliverable(s) of this task:

D01 Outcomes of CT examination of CICC conductors and joints samples and associated analyses:

- Structural integrity characterization
- Local void statistics
- Strand trajectory reconstruction
- Development of an XCT protocol for CICC joints

Annual report on XCT analysis of CICC cables and joints.

Real costs (excluding overheads) Total 0.1+0.3 ppy & 5 kEuro HW

OUTLINE

- Application of X-ray tomography on a HTS CICC prototype
 - Scanning configuration optimization
 - Room vs. liquid nitrogen comparison
 - Reconstruction of a relevant fragment of HTS cable
 - Quantitative analysis of the HTS cable components
- Tomography analysis of microstructural integrity of joints of HTS tapes
- Micro-tomography vs micro-laminography scanning configurations
- Additional work: refining of high resolution tomography on advanced SC strands

Center for Advanced X-ray Imaging

Sub-micron resolution tomograph



Industrial tomograph (high energy)





3D tomography & composition mapping - material science



Gantry tomograph: bio-applications

X-ray tomography analysis of an ENEA HTS prototype



CT on HTS CICC at RT & LN



CT section rough image



CT section filtered image

ENEA HTS DEMO Prototype 180kV, 10 microns/voxel

Room temperature



Liquid nitrogen



XCT cross-sections 180 kV vs 250 kV

180kV



250 kV



High penetration power XCT system is better suited for HTS CICC tomography analysis

2D & 3D movies of HTS CICC tomography images

Cu wires trajectory reconstruction

- It is used Circle Hough Transform (CHT) slicewise
- After connecting all the centroids of adjacent slices, the resulted trajectory is smoothed using Savitzky-Golay algorithm





Image processing towards finite element discretization for Multiphysics simulations.



Cu wires trajectory reconstruction on a ~400 mm section



finite element discretization

HTS tape joints analysis of microstructural integrity by tomography analysis

HTS tape joints - tomography analysis

The sample consists of two 4-mm-wide copper-stabilized REBCO tapes joined in a Spark Plasma Sintering (SPS) machine. A thin layer of bulk HTS material was added.







It is possible to evaluate the contact resistance based on the actual contact area determined from tomography measurements

X-ray micro-laminography (µXCL)

- generalization of µXCT that permits the inspection of planar objects
- μ XCL avoids using projections from angles closest to the sample coated surface leading thus to reconstructions with fewer artefacts.



Increased contribution of the information containing X-ray interaction with the W coating as seen in the overall grey level histogram as depicted in the red circles.

3D micro-tomography versus X-ray micro-laminography scanning configurations

X-ray micro-laminography alternative configurations



Sample placed on a tilt rotation axis

Sample placed on a vertical rotation axis but with an offset of the detector

HTS tape joints - laminography analysis

Laminography cross-sections showing discontinuities in the tape-bulk material interfaces









Тор







2D movie of HTS tape joints laminography images

Highly space resolved tomography on advanced Bronze(Cu-Sn) strands

HTS tape joints - laminography analysis

Laminography cross-sections showing discontinuities in the tape-bulk material interface



The sample consists of two HTS tapes with a thicker bulk HTS layer in between. Joining was done in a Spark Plasma Sintering (SPS) machine

Bronze filaments (before heat treatment)



Top View with Nb3Sn cores measurements

Bronze filaments (after heat treatment)



Top View with filament diameter measurement

Top View with Nb3Sn cores measurements

Comparison of before & after heat treatment



SC alloy has a reduced effective X-ray attenuation factor

TS 2020

Proposed tasks

In 2020 we will conduct X-ray tomography (XCT) analysis on CICC conductors and joints relevant for the DEMO magnet system. New samples are already provided by ENEA and CEA, respectively. It is planned that other samples will be provided within the EU-CN cooperation.

ENEA DEMO prototypes:

- Tomography analysis of sample(s) of low-field type (higher ratio of Cu vs Nb3Sn than in the already XCT scanned sample).

CEA DEMO prototypes:

- Study of contact mapping dependence on compaction
- XCT analysis of joint structures relevant for DEMO magnet system.

Thank you for attention!